

1. Record Nr.	UNINA9910455546103321
Titolo	Maritime boundary disputes, settlement processes, and the law of the sea [[electronic resource] /] / edited by Jon M. Van Dyke and Seoung-Yong Hong
Pubbl/distr/stampa	Leiden ; ; Boston, : Martinus Nijhoff Publishers, c2009
ISBN	1-282-40086-X 9786612400865 90-474-2689-4
Descrizione fisica	1 online resource (324 p.)
Collana	Publications on ocean development ; ; 65
Altri autori (Persone)	Van DykeJon M HongSeoung-Yong
Disciplina	[22] 341.4/48 341.4/48 343.096
Soggetti	Territorial waters Economic zones (Law of the sea) Boundary disputes Continental shelf Law of the sea Electronic books.
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Preliminary Materials / Seoung-Yong Hong and Jon M. Van Dyke -- Chapter I. Climate Change, Sea Level Rise And The Coming Uncertainty In Oceanic Boundaries: A Proposal To Avoid Conflict / David D. Caron -- Chapter II. The Trouble With Islands: The Definition And Role Of Islands And Rocks In Maritime Boundary Delimitation / Clive Schofield -- Chapter III. Disputes Over Islands And Maritime Boundaries In East Asia / Jon M. Van Dyke -- Chapter IV. Sino-Japanese Jurisdictional Delimitation In East China Sea: Approaches To Dispute Settlement / Ji Guoxing -- Chapter V. Some Thoughts On Maritime Boundary Delimitation / Masahiro Miyoshi -- Chapter VI. Intertemporal Law, Recent Judgments And Territorial Disputes In Asia / Seokwoo Lee --

Chapter VII. Some Legal Aspects Of Territorial Disputes Over Islands / Kentaro Serita -- Chapter VIII. Okinotorishima: A Rock Or An Island? Recent Maritime Boundary Controversy Between Japan And Taiwan/China / Yann-Huei Song -- Chapter IX. Canada-U.S. International Ocean Law Relations In The North Pacific: Disputes, Agreements And Cooperation / Ted L. Mcdorman -- Chapter X. Maritime Boundary Delimitation And Cooperative Management Of Transboundary Hydrocarbons In The Ultra-Deepwaters Of The Gulf Of Mexico / Richard J. Mclaughlin -- Chapter XI. The Law Of The Sea Convention And The Antarctic Treaty System: Constraints Or Complementarity? / Marcus Haward -- Chapter XII. The Contribution Of The International Tribunal For The Law Of The Sea To International Law / Helmut Tuerk -- Chapter XIII. The Tomimaru Case: Confiscation And Prompt Release / Bernard H. Oxman -- Index / Seoung-Yong Hong and Jon M. Van Dyke -- Publications On Ocean Development / Seoung-Yong Hong and Jon M. Van Dyke.

Sommario/riassunto

A surprising number of maritime boundaries remain unresolved, and a range of reasons can be cited to explain why the process of delimiting these boundaries has been so slow. This volume addresses and analyzes some of these reasons, focusing on some of the volatile disputes in Northeast Asia and in North America. Scholars from Asia, the United States, and Europe grapple with festering controversies and apply insights gained from resolved disputes to those that remain unresolved. Islands continue to haunt this process, and the way in which they should affect maritime boundaries remains in dispute. The United States has a number of disputed boundaries with its neighbors to the north and south, and these are examined. Antarctica is a concern of all nations, and the regimes governing the Southern Ocean surrounding Antarctica are analyzed. The International Tribunal for the Law of the Sea was created to allow countries to resolve their disputes peacefully, and two chapters look at how this new court is operating. The impact of sea-level rise on maritime boundaries is given special attention in the opening chapter. This volume presents a wonderful collection of provocative chapters written by the top scholars in the field of International Ocean Law. It should help scholars, students, and decision makers to understand the current state of this field and to move some of the difficult disputes toward resolution.

2. Record Nr.	UNINA9910144578403321
Titolo	Nanoscale calibration standards and methods [[electronic resource]] : dimensional and related measurements in the micro- and nanometer range // edited by Gunter Wilkening, Ludger Koenders
Pubbl/distr/stampa	Weinheim ; ; [Chichester?], : Wiley-VCH, c2005
ISBN	1-280-85401-4 9786610854011 3-527-60666-1 3-527-60687-4
Descrizione fisica	1 online resource (543 p.)
Altri autori (Persone)	KoendersLudger WilkeningGunter
Disciplina	620.50287
Soggetti	Microstructure - Measurement Nanostructured materials - Measurement Scientific apparatus and instruments - Calibration Stereology Electronic books.
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Conference proceedings.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Nanoscale Calibration Standards and Methods; Contents; List of Contributors; Part I Instrumentation - Overview; 1 Metrological Scanning Probe Microscopes - Instruments for Dimensional Nanometrology; 1.1 Introduction; 1.2 High-Resolution Probing Systems; 1.2.1 Sensor Objective with Beam Deflection Detection; 1.2.2 Sensor Objective with Piezolever Module; 1.2.3 Sensor Objective with Tuning Fork Module; 1.2.4 Sensor Head for Combined Scanning Probe and Interference Microscopy; 1.3 Metrology Systems Based on Scanning Probe Microscopes; 1.3.1 Scanning Force Microscopes of Type Veritekt 1.3.2 Metrological Large Range Scanning Force Microscope1.4 Summary; Acknowledgments; References; 2 Nanometrology at the IMGC; 2.1 Introduction; 2.2 Surface Metrology; 2.2.1 Scanning Probe Microscopy; 2.2.2 Optical Diffractometry; 2.2.3 Stylus Profilometry; 2.3 Atomic Scale Metrology; 2.3.1 Lattice Parameter of Silicon; 2.3.2

Combined Optical and X-Ray Interferometry (COXI); 2.4 Phase-Contrast Topography; 2.4.1 Detection of Small Lattice Strain; 2.4.2 Phase-Contrast Imaging; 2.5 Nanobalance; 2.6 Conclusions; References; 3 Metrological Applications of X-ray Interferometry; 3.1 Introduction 3.2 Measurement of Non-linearity in Optical Interferometers 3.3 Combined Optical and X-ray Interferometry; 3.4 Measurement of Small Angles; 3.5 X-ray Interferometry and Scanning Probe Microscopy; 3.6 Conclusions; References; Part II Instrumentation - Long-range Scanning Probe Microscopes; 4 Advances in Traceable Nanometrology with the Nanopositioning and Nanomeasuring Machine; 4.1 Introduction; 4.2 Design and Operation; 4.3 Uncertainty Budget; 4.4 Focus Sensor; 4.5 Measuring Opportunities and Performance with Focus Sensor; 4.6 Focus Probe with SFM Cantilever; 4.7 Conclusion; Acknowledgements References 5 Coordinate Measurements in Microsystems by Using AFM-Probing: Problems and Solutions; 5.1 Introduction; 5.2 Realizing CMMs for Microsystems; 5.3 Problems and Solutions; 5.3.1 Dynamics of Positioning System; 5.3.2 CMM: One-Millimeter Scan; 5.3.3 Measuring Strategies; 5.4 Conclusion and Outlook; References; 6 Metrological Large Range Scanning Force Microscope Applicable for Traceable Calibration of Surface Textures; 6.1 Introduction; 6.2 Instrumentation; 6.2.1 Principle; 6.2.2 Metrological Properties; 6.2.3 Traceability; 6.2.4 Specially Designed Features 6.3 Measurement Result of a 2D-Grating Standard 6.3.1 Measurement Strategy; 6.3.2 Data Evaluation; 6.3.3 Measurement Result of the Mean Pitch Value; 6.3.4 Measurement of the Local Pitch Variation; 6.4 A Selected Measurement Result of a Microroughness Standard; 6.4.1 Measurement Result of a Glass Flatness Standard; 6.4.2 Measurement of a PTB Microroughness Standard; 6.4.3 Comparison of the Roughness Measurement Results Derived from SFM and Stylus Instruments Using Gaussian Filter; 6.4.4 Comparison Using Morphological Filters; 6.4.5 Evaluation Results Using PTB Reference Software 6.5 Outlook and Conclusion

Sommario/riassunto

The quantitative determination of the properties of micro- and nanostructures is essential in research and development. It is also a prerequisite in process control and quality assurance in industry. The knowledge of the geometrical dimensions of structures in most cases is the base, to which other physical and chemical properties are linked. Quantitative measurements require reliable and stable instruments, suitable measurement procedures as well as appropriate calibration artefacts and methods. The seminar "NanoScale 2004" (6th Seminar on Quantitative Microscopy and 2nd Seminar on Nanoscal
